

Fraunhofer Institute for Reliability and Microintegration IZM

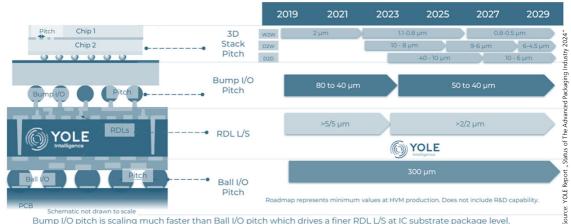
Dr. Manuela Junghähnel

Electronic Packaging Days 2025

Navigating the Future: Innovation and Roadmapping in Wafer Level Packaging

Advanced packaging roadmap: I/O pitch and RDL L/S

A typical flip-chip IC Substrate



Bump I/O pitch is scaling much faster than Ball I/O pitch which drives a finer RDL L/S at IC substrate package level.





Beide 2

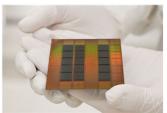
Semiconductor packaging technology is the key pillar if the future is digital

Goals

- the continued reduction of interconnection pitch enabled by TSVs, TMVs, microbumps, and more aggressively, hybrid bonding.
- Further shrinking via diameter and wafer thickness.

Driver Technologies

- Hybrid bonding for 3D SoCs.
- Chiplet-based and heterogeneous architectures
- Co-Packaged Optics
- Glass is gaining momentum as a core substrate material
- Toward 3.5D Packaging: converging toward platforms that combine 2.5D and 3D integration



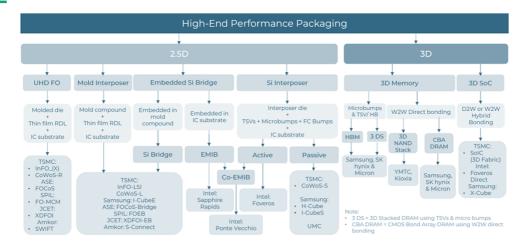


otos: Sylivia Wolf





Advanced packaging roadmap: Technologies for 2.5 and 3D integration







The APECS pilot line – European chiplet innovation

Advanced Packaging and Heterogeneous Integration for Electronic Components and Systems









Fraunhofer IZM - Wafer Level Integration

Infrastructure & Process Capabilities

ISO 9001-certified process lines at two locations (Berlin & Dresden) for process development, material and equipment evaluation as well as R&D and industrial services on automated and semi-automated production equipment

WLSI Berlin:

Vast variety of materials, processes and wafer materials / sizes suited for R&D prototyping and small volume manufacturing, TRL 2 – 9

ASSID Dresden:

Industry-compatible process line for 200 / 300mm Si and glass wafers and prototyping for small to medium volume manufacturing, TRL 6 – 9



Fraunhofer IZM (Berlin)





1000 m² clean room area (ISO 4-6) Wafer sizes: 100, 150, 200 mm (partially 300 mm)



Fraunhofer IZM-ASSID (Dresden)





900 m² clean room area (ISO 6-7) Wafer sizes: 200 mm + 300 mm





Berlin

CERTIFIED

Dresden

WLSI Research Infrastructure Berlin

100-200mm clean room (expanding 300mm capabilities)

Process line for advanced prototyping and pilot manufacturing

- 2.5D / 3D integration (SiP. CSP) for a variety of semiconductor materials
- · Polymer/Cu-based high density multilayer RDL
- Silicon interposer with application specific TSV integration (via middle, via last, back side TSV) and Glass interposer with TGV, both with high density. multi-layer RDL
- Advanced interconnect solutions for photonics, RF and MEMS packaging and power (Cu/Sn(Ag), Cu/Sn, Ni/Au, sulf, or cvan, Au, AuSn, NPG, In, InSn)
- Temporary/Permanent wafer bonding (adhesive, solder, anodic, direct)
- High accuracy flip-chip assembly (D2D, D2W)
- Fan-In and Fan-Out wafer level packaging (high density RDL first/last, multi chip (Si, GaAs, GaN, SiC, ...))
- High energy particle, x-ray and IR detector module flip-chip interconnects and assembly
- Wafer-level MEMS packaging and prototyping of MEMS sensors
- Development of photonic systems (design, hybrid EIC/PIC integration, characterization)

ISO 9001:2015 certified | MES



Wafer Processing and Assembly Clean Room 1000 m² ISO 3 - ISO 5

100–200mm process line for 2.5D/3D heterogeneous wafer level system integration (expanding 300mm capabilities)

Capacity for several 100 wafers per year with TRL 2 – 9







ASSID Research Infrastructure Dresden

200/300mm clean room

Process line adjusted to development, prototyping and low volume manufacturing under industrial manufacturing conditions.

- 3D wafer-level SiP. CSP
- Application-specific Cu-TSV integration: via middle, via last, backside
- Si interposer with TSV, multi-layer RDL, micro-cavities, integrated passives
- Glass interposer w/wo TGV, multi-layer RDL and μ-interconnects
- High-density, multi-pitch & size micro-bump or pillar interconnects (Cu. SnAg, Au, Ni)
- Pre-assembly: thinning, thin wafer handling, laser & mechanical singulation
- 3D assembly: D2D, D2W, W2W, 3D WL stacking
- Temporary/permanent wafer bonding (adhesive, soldering, direct)
- Direct bond interconnects (DBI) W2W. D2W.
- High density multi-layer polymer RDL for advanced high density flex, flex/silicon & RDL-1st FOWLP applications



R&D clean room ASSID1: 800m2 ISO-class 6, lab space: 300 m² ISO-class 7

Leading edge process line for 2.5D/3D heterogeneous wafer level system integration equipment compatible to run 200mm/300mm wafer-FOUP

Capacity for several 100-1000 wafers per year with TRL 6 – 9

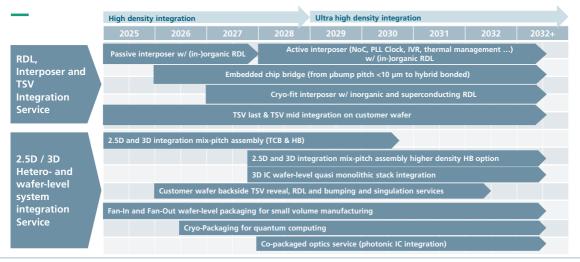
ISO 9001:2015 certified | MES







Technology Roadmap: 300 mm 2.5 und 3D Wafer Integration Technologies









Technologies & Services

- 2.5D/3D integration up to 300 mm, fan-in /-out wafer-level packaging, UHD interposer, hybrid bonding, micro-bumping
- Access to design kits (PDK/ADK), advanced prototyping & pilot production



Chiplets & Components

- Design and manufacturing of chiplets for client use
- Combining CMOS, RF, MEMS, photonics, sensors, and more
- Versatile platform supporting chiplets from multiple sources with standard and custom interfaces like UCle and BoW

Demonstrators



Four demonstrators show a seamless process chain:

- HPC: High-performance computing module with hybrid chiplet integration
- Sensor: Multi-material sensor system with heterogeneous & QMI integration
- Photonics: High-speed photonic module with InP-EML arrays & photonic wire bonding
- RF: RF module up to 300 GHz, integrating InP, GaN, SiGe, BiCMOS & advanced packaging



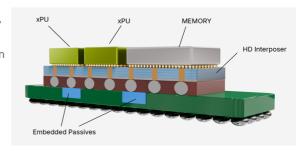




Demonstrator Example: High Performance Computing (WP 6.1)

Lead: Fraunhofer IIS and IZM-ASSID

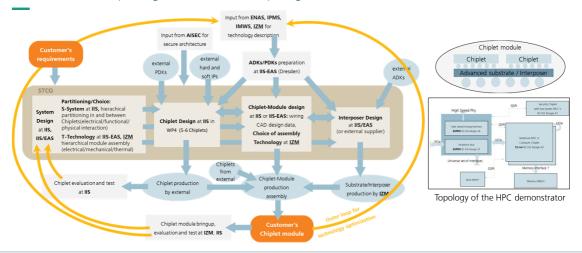
- STCO concepts will be enabled and used for a first-time right functionality from the design to manufacturing and verification measurements comparing simulations with the results.
- The institutes IIS & AISEC are involved for chiplet architecture specification, fabrication and test and packaging development and interposer and assembly developments.
- IZM, IZM-ASSID, IPMS and IIS, IIS-EAS, AISEC focus on the overall targets for system architecture, STCO and chiplet/interposer interface.
- A security analysis will be carried out by AISEC. The chiplets to be integrated in this demonstrator are designed in WP4 (STCO design).







Demonstrator Example: High Performance Computing (WP 6.1)



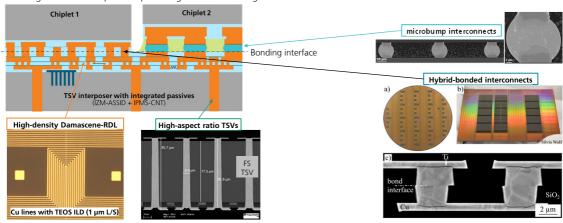




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Demonstrator Example: High Performance Computing

Heterogeneous mixed-pitch chiplet integration for ultrahigh I/O densities

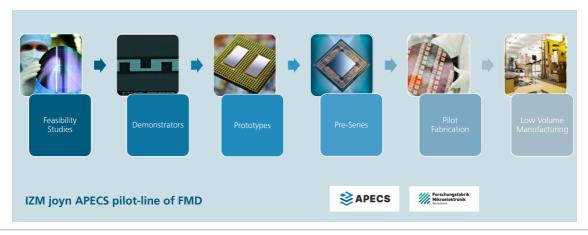








IZM Research and Development Services on Wafer Level provided to Industry







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Thank you for your attention



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